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FEATURES

Avalanche Rugged Technology

Rugged Gate Oxide Technology

• Lower Input Capacitance

Improved Gate Charge

• Extended Safe Operating Area

• Lower Leakage Current : 10 μA (Max.) @ $V_{DS} = 100 V$

• Lower $R_{DS(ON)}$: 0.176 Ω (Typ.)

$BV_{DSS} = 100 V$
$R_{DS(on)} = 0.22 \Omega$
$I_D = 2.3 A$



1. Gate 2. Drain 3. Source

Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage	100	V
,	Continuous Drain Current (T _C =25°C)	2.3	
I _D	Continuous Drain Current (T _C =70°C)	1.85	А
I _{DM}	Drain Current-Pulsed (1)	18	Α
V_{GS}	Gate-to-Source Voltage	±20	V
E _{AS}	Single Pulsed Avalanche Energy (2)	105	mJ
I _{AR}	Avalanche Current (1)	2.3	Α
E _{AR}	Repetitive Avalanche Energy (1)	0.27	mJ
dv/dt	Peak Diode Recovery dv/dt (3)	6.5	V/ns
	Total Power Dissipation (T _C =25°C) *	2.7	W
P_{D}	Linear Derating Factor *	0.022	W/°C
Operating Junction and			
T_J, T_{STG}	Storage Temperature Range	- 55 to +150	°c
_	Maximum Lead Temp. for Soldering	000	
T _L Purposes, 1/8" from case for 5-seconds		300	

Thermal Resistance

Symbol	Characteristic	Тур.	Max.	Units
$R_{ heta JA}$	Junction-to-Ambient *		46.3	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount).



Electrical Characteristics ($T_C=25$ $^{\circ}C$ unless otherwise specified)

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition
BV _{DSS}	Drain-Source Breakdown Voltage	100			V	V_{GS} =0V, I_D =250 μ A
$\Delta BV/\Delta T_J$	Breakdown Voltage Temp. Coeff.		0.09		V/ °C	I _D =250μA See Fig 7
$V_{GS(th)}$	Gate Threshold Voltage	1.0	-	2.0	V	$V_{DS} = 5V, I_{D} = 250 \mu A$
	Gate-Source Leakage, Forward			100	nA	V _{GS} =20V
I _{GSS}	Gate-Source Leakage, Reverse			-100	ш	V _{GS} =-20V
	Drain to Source Leekage Current			10		V _{DS} =100V
I _{DSS}	Drain-to-Source Leakage Current			100	μΑ	V_{DS} =80V, T_{C} =125 $^{\circ}$ C
	Static Drain-Source					\\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
R _{DS(on)}	On-State Resistance			0.22	Ω	$V_{GS} = 5V, I_D = 1.15A$ (4)
g _{fs}	Forward Transconductance		4.6		Ω	$V_{DS} = 40V, I_{D} = 1.15A$ (4)
C _{iss}	Input Capacitance		340	440		\\
C _{oss}	Output Capacitance		90	115	рF	$V_{GS}=0V, V_{DS}=25V, f=1MHz$
C _{rss}	Reverse Transfer Capacitance		39	50		See Fig 5
t _{d(on)}	Turn-On Delay Time		5	20		\/ F0\/ L 0.2\
t _r	Rise Time		10	30		$V_{DD} = 50V, I_{D} = 9.2A,$
t _{d(off)}	Turn-Off Delay Time		19	50	ns	$R_G=9 \Omega$
t _f	Fall Time		9	30		See Fig 13 (4)(5)
Q_g	Total Gate Charge		10.2	15		V_{DS} =80V, V_{GS} =5V,
Q_gs	Gate-Source Charge		1.7		nC	I _D =9.2A
Q_{gd}	Gate-Drain ("Miller") Charge		6.0	-		See Fig 6 & Fig 12 (4)(5)

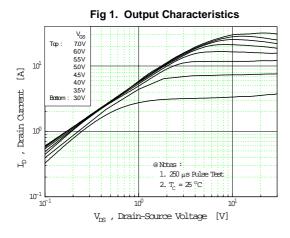
Source-Drain Diode Ratings and Characteristics

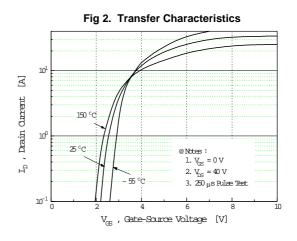
Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition	
I _S	Continuous Source Current		-	2.3		Integral reverse pn-diode	
I _{SM}	Pulsed-Source Current (1)		1	18	Α	А	in the MOSFET
V_{SD}	Diode Forward Voltage (4)		1	1.5	V	T _J =25 °C,I _S =2.3A,V _{GS} =0V	
t _{rr}	Reverse Recovery Time		98		ns	T _J =25 °C,I _F =9.2A	
Q_{rr}	Reverse Recovery Charge		0.34		μС	$di_F/dt=100A/\mu s$ (4)	

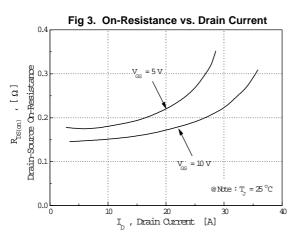
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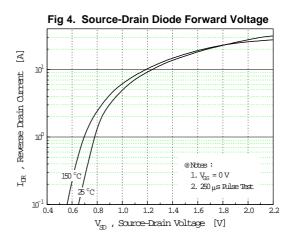
- ① Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature
- $^{(2)}$ L=30mH, I $_{AS}$ =2.3A, V $_{DD}$ =25V, R $_{G}$ =27 $\Omega,$ Starting T $_{J}$ =25 $^{\circ}C$
- $3 I_{SD} \le 9.2 A$, di/dt $\le 300 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ $^{\circ}C$
- 4 Pulse Test : Pulse Width = 250μ s, Duty Cycle $\leq 2\%$
- 5 Essentially Independent of Operating Temperature

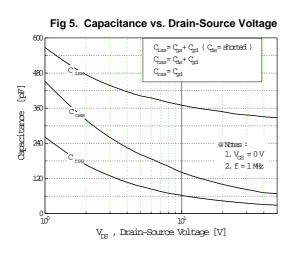


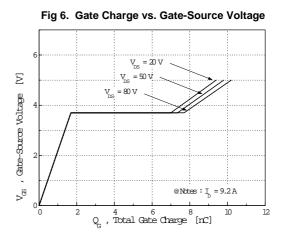




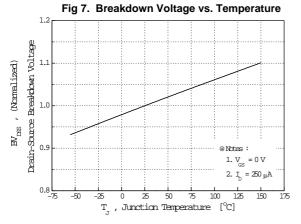


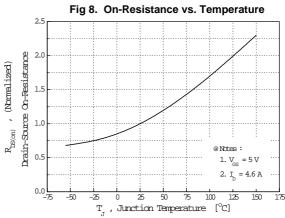


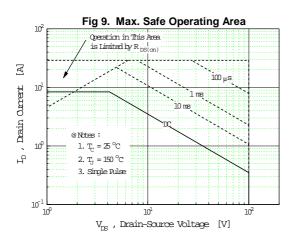


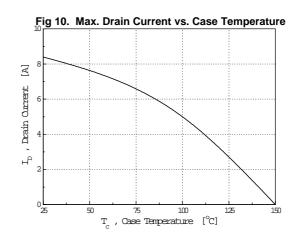


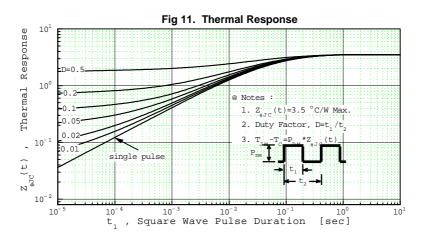














 R_1

 $\begin{array}{c} \text{Current Sampling } (I_G) \\ \text{Resistor} \end{array}$

Charge

** Current Regulator "Same Type as DUT V_{GS} V_{GS} V_{GS} V_{GS} V_{GS} V_{GS} V_{GS} V_{GS} V_{GS}

Fig 12. Gate Charge Test Circuit & Waveform

Fig 13. Resistive Switching Test Circuit & Waveforms

 $\begin{array}{c} \text{Current Sampling } (I_D) \\ \text{Resistor} \end{array}$

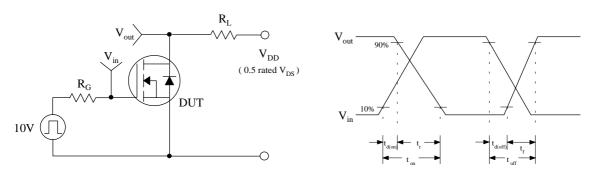


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

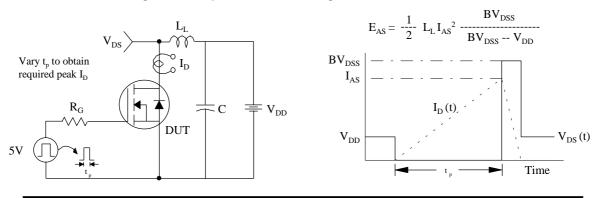
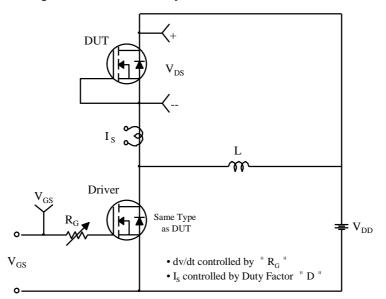
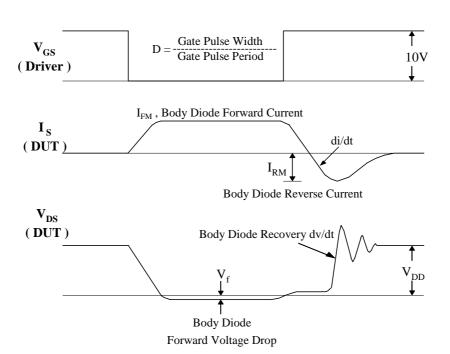




Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms







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